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Department of Commerce Patent and Trademark Office

Atty. Docket ...o. P24855

Application No. 10/759,160

FORMATION DISCLOSURE STATEMENT
BY APPLICANT
(Use several sheets if necessary)

Silke KOHLHASE et al.

Applicant

Filing Date January 20, 2004 Group 1615

## CLA **EXAMINER FILING DATE** SUBCLASS INITIAL **DOCUMENT NUMBER** DATE NAME SS IF APPROPRIATE /SJL/ RIEDEL et al. 2004/ 0 2 4 1 1 0 5 12/02/04 *1*SJL/ 7 2004/ 0 5 9 1 5 03/25/04 GERS-BARLAG et al. /SJL/ 2002/ 9 7 2 1 3 12/26/02 SCHMENGER et al. 0 1 **FOREIGN PATENT DOCUMENTS TRANSLATION** DOCUMENT NUMBER DATE COUNTRY CLASS **SUBCLASS** YES /SJL/ 03/26/03 E.P.O., 1. 2 9 5 5 8 9 10/15/03 E.P.O. /SJL/ .1 3 5 2 6 4 1 01/13/00 **GERMANY** 9 9 3 4 6 1 3 6 /SJL/

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\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Atty. Docket No. P24855

Applicant

Application No. 10/759,160

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